

FAST GATE TURN-OFF THYRISTORS

Thyristors in TO-238AA envelopes with electrically isolated metal baseplates capable of being turned both on and off via the gate. They are suitable for use in high-frequency inverters, power supplies, motor control etc. The devices have no reverse blocking capability. For reverse blocking operation use with a series diode, for reverse conducting operation use with an anti-parallel diode.

QUICK REFERENCE DATA

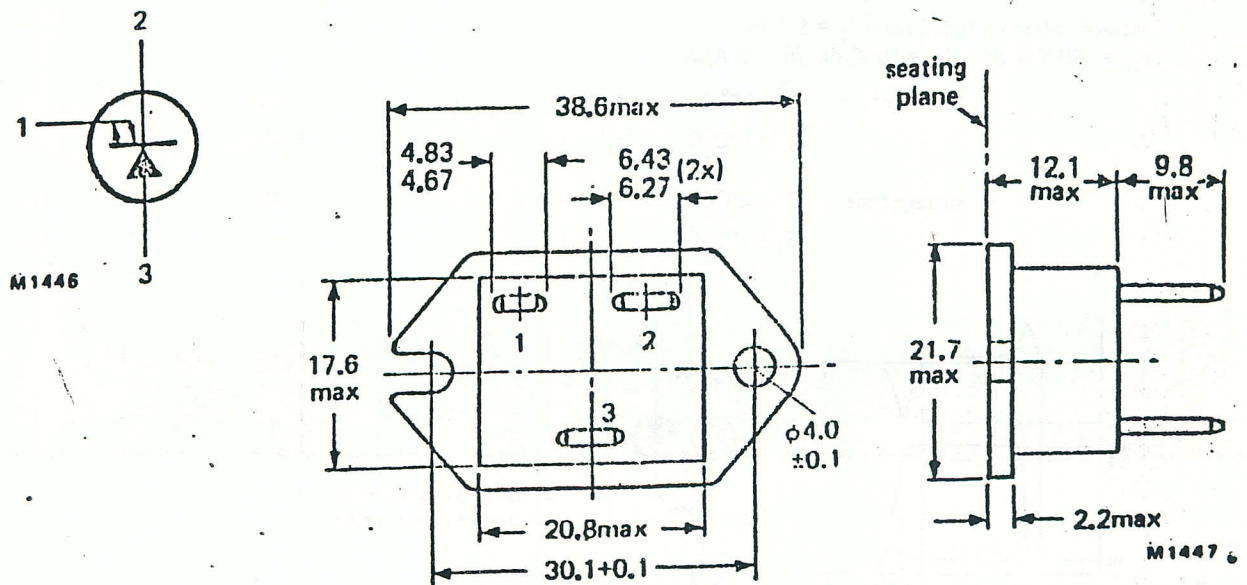
		BT 700 SERIES			
		BT 700-850R	1000R	1200R	
Repetitive peak off-state voltage	V_{DRM}	max. 850	1000	1200	V
Non-repetitive peak on-state current	I_{TSM}	max.	150		A
Controllable anode current	I_{TCRM}	max.	120		A
Average on-state current	$I_{T(AV)}$	max.	25		A
Fall time	t_f	<	300		ns

MECHANICAL DATA

Dimensions in mm

Fig.1 TO-238AA

blue binder, tab 9



- Pin 1 = gate (AMP 187 series)
 - Pin 2 = cathode (AMP 250 series)
 - Pin 3 = anode (AMP 250 series)
- Baseplate is electrically isolated.

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RATINGS

Limiting values in accordance with the absolute Maximum System (IEC134)

Anode to cathode		BTV60-850R	1000R	1200R	
Transient off-state voltage	V_{DSM}	max. 1000	1100	1300	V*
Repetitive peak off-state voltage	V_{DRM}	max. 850	1000	1200	V*
Working off-state voltage	V_{DW}	max. 600	800	1000	V*
Continuous off-state voltage	V_D	max. 500	650	750	V*
Average on-state current (averaged over any 20 ms period) up to $T_{mb} = 70^\circ C$	$I_{T(AV)}$		max. 25		A
Controllable anode current	I_{TCRM}		max. 120		A
Non-repetitive peak on-state current t = 10 ms; half-sinewave; $T_j = 120^\circ C$ prior to surge	I_{TSM}		max. 150		A
$I^2 t$ for fusing; t = 10 ms	$I^2 t$		max. 112		A ² s
Total power dissipation up to $T_{mb} = 25^\circ C$	P_{tot}		max. 120		W
Gate to cathode					
Repetitive peak on-state current $T_j = 120^\circ C$ prior to surge gate-cathode forward; t = 10 ms; half-sinewave	I_{GFM}		max. 35		A
gate-cathode reverse; t = 20 μs	I_{GRM}		max. 50		A
Average power dissipation (averaged over any 20 ms period)	$P_{G(AV)}$		max. 10		W
Temperatures					
Storage temperature	T_{stg}		-40 to +150		$^\circ C$
Operating junction temperature	T_j		max. 120		$^\circ C$
ISOLATION**					
R.M.S. isolation voltage	V_{isol}		min. 2500		V
THERMAL RESISTANCE					
From mounting base to heatsink; with heatsink compound	$R_{th\ mb-h}$	=	0.3		K/W
From junction to mounting base	$R_{th\ j-mb}$	=	0.8		K/W

* Measured with gate-cathode connected together.
** From baseplate to all terminals strapped together.

CHARACTERISTICS

Anode to cathode

On-state voltage

$I_T = 20 \text{ A}; I_G = 0.5 \text{ A}; T_j = 120 \text{ }^\circ\text{C}$ $V_T < 2.2 \text{ V}^*$

Rate of rise of off-state voltage that will not trigger any off-state device; exponential method

$V_D = 2/3 V_{Dmax}; V_{GR} = 5 \text{ V}; T_j = 120 \text{ }^\circ\text{C}$ $dV_D/dt < 10 \text{ kV}_\mu\text{s}$

Rate of rise of off-state voltage that will not trigger any device following conduction, linear method

$I_T = 60 \text{ A}; V_D = V_{DRMmax}; V_{GR} = 10 \text{ V}; T_j = 120 \text{ }^\circ\text{C}$ $dV_D/dt < 1.0 \text{ kV}_\mu\text{s}$

Off-state current

$V_D = V_{Dmax}; T_j = 120 \text{ }^\circ\text{C}$ $I_D < 5.0 \text{ mA}$

Latching current; $T_j = 25 \text{ }^\circ\text{C}$

$I_L \text{ typ. } 5.0 \text{ A}^*$

Gate to cathode

Voltage that will trigger all devices

$V_D = 12 \text{ V}; T_j = 25 \text{ }^\circ\text{C}$ $V_{GT} > 1.5 \text{ V}$

Current that will trigger all devices

$V_D = 12 \text{ V}; T_j = 25 \text{ }^\circ\text{C}$ $I_{GT} > 500 \text{ mA}$

Minimum reverse breakdown voltage

$I_{GR} = 1.0 \text{ mA}$ $V_{(BR)GR} > 10 \text{ V}$

Switching characteristics (resistive load)

Turn-on when switched to $I_T = 50 \text{ A}$ from $V_D = 250 \text{ V}$ with $I_{GF} = 2.5 \text{ A}; T_j = 25 \text{ }^\circ\text{C}$

delay time $t_d < 0.5 \text{ } \mu\text{s}$
rise time $t_r < 2.0 \text{ } \mu\text{s}$

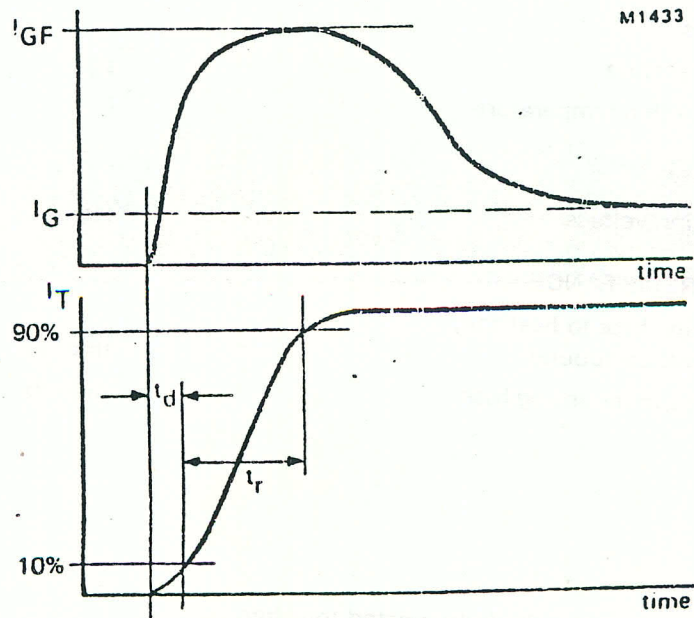


Fig.2 Waveforms.

*Measured under pulse conditions to avoid excessive dissipation.

**Below latching level the device behaves like a transistor with a gain dependent on current.

Switching characteristics (inductive load)

Turn-off when switched from $I_T = 50$ A to $V_D = V_{Dmax}$;
 $V_{GR} = 10$ V; $L_G \leq 0.5 \mu\text{H}$; $L_S \leq 0.25 \mu\text{H}$; $T_j = 25^\circ\text{C}$

storage time	t_s	<	1.0
fall time	t_f	<	0.3
peak reverse gate current	I_{GR}	<	25

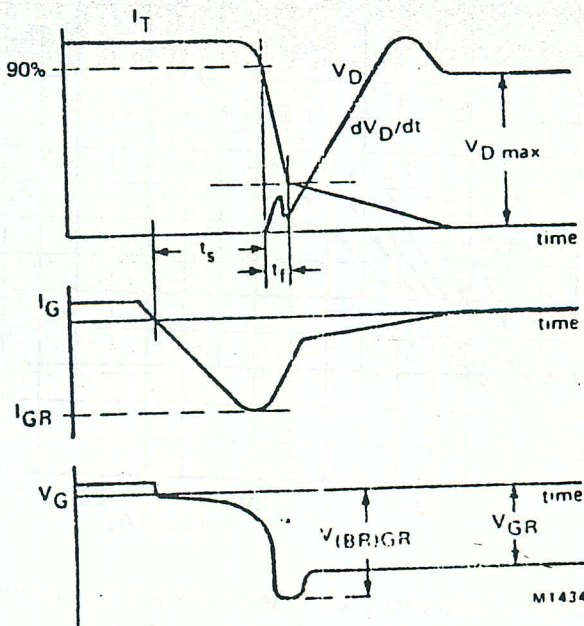


Fig.3 Wave

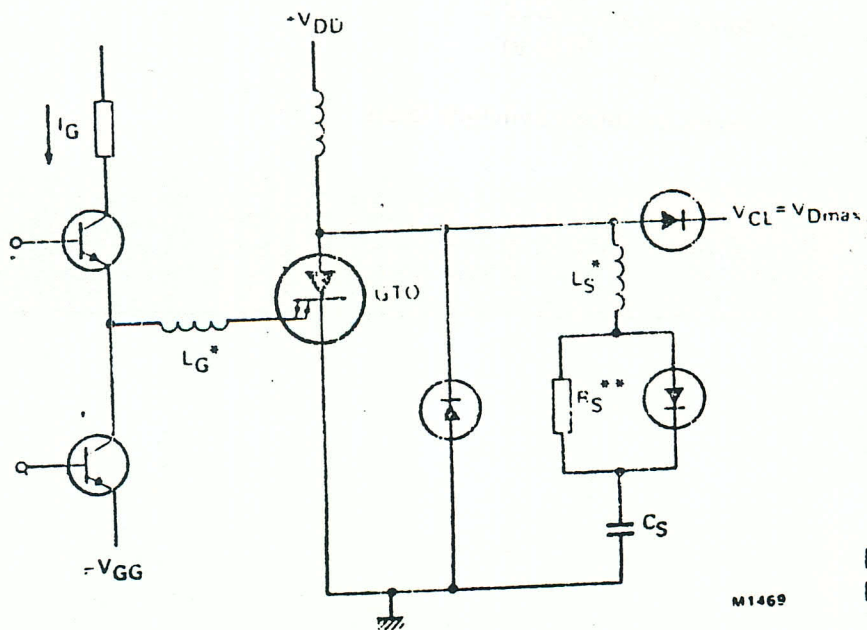


Fig.4 Inductive load test

*Indicates stray series inductance only.
 **Minimum permissible GTO on-time (μs) = $R_S (\Omega) \times C_S (\mu\text{F}) \times 5$.

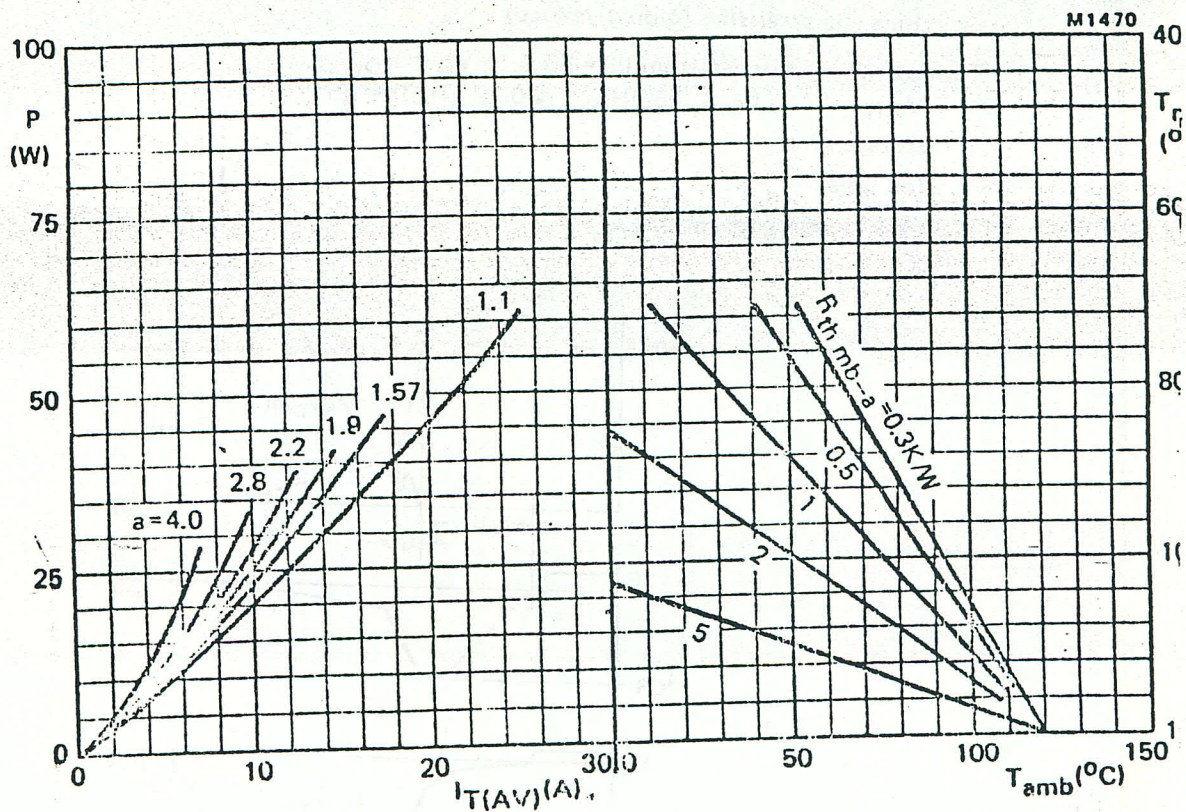


Fig.5 The right hand part shows the interrelationship between the power (derived from the left-hand part) and the maximum permissible temperatures.

$$a = \text{form factor} = \frac{I_T(\text{RMS})}{I_T(\text{AV})}$$

P = power excluding switching losses.

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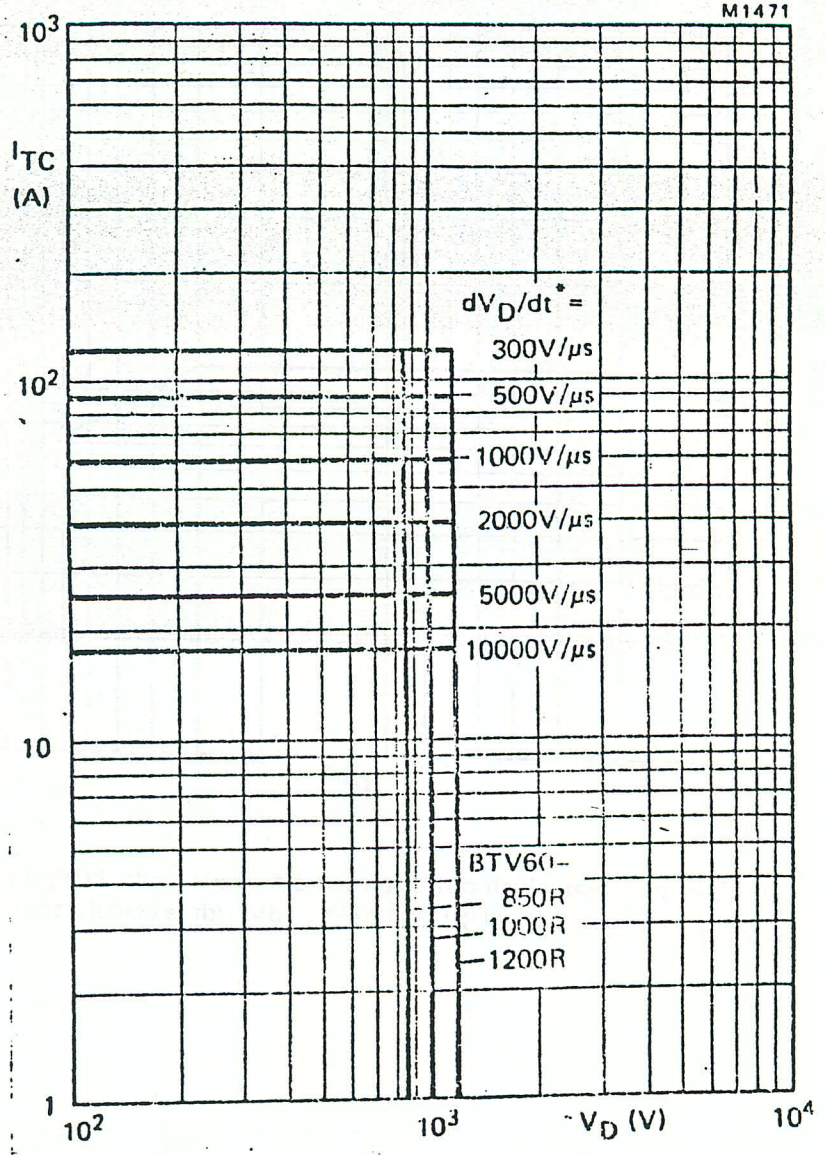


Fig.6 Anode current which can be turned off versus anode voltage; inductive load; $V_{GR} = 10$ V; $L_G \leq 0.5 \mu H$; $L_S \leq 0.25 \mu H$; $T_j = 120^\circ C$.
 * dV_D/dt is calculated from I_T/C_S .

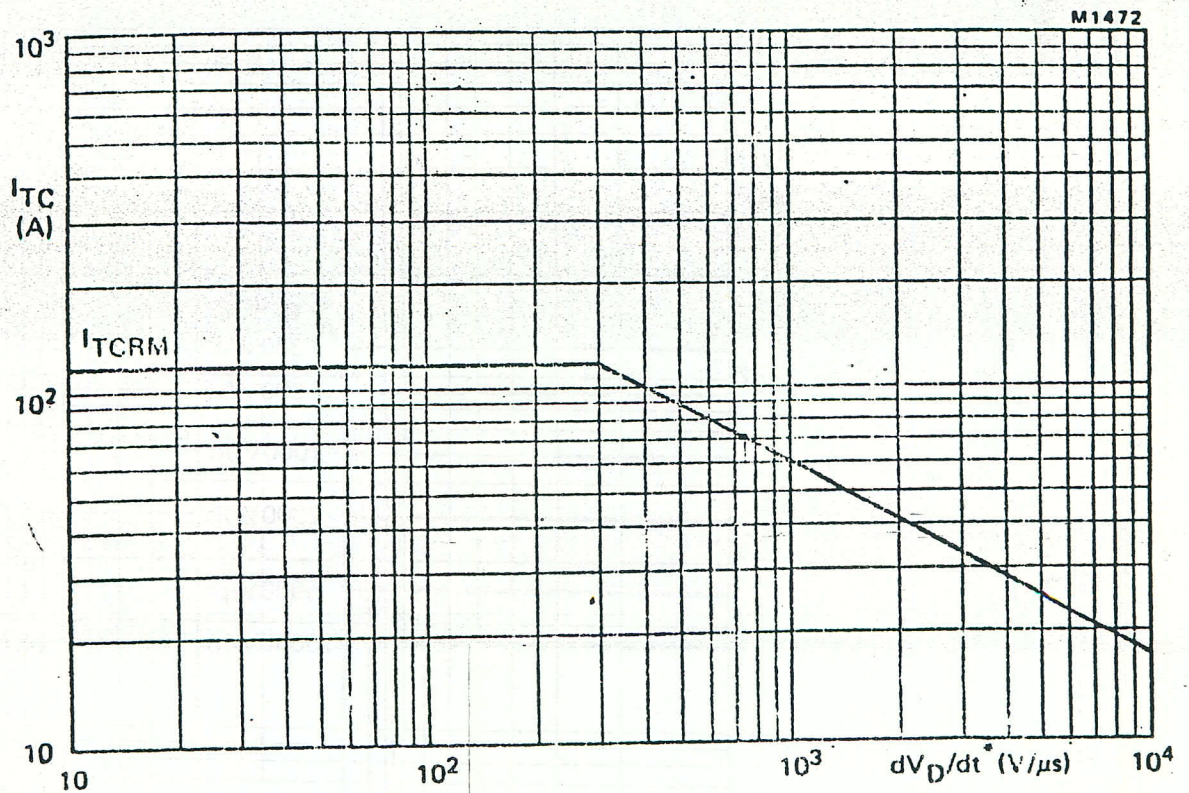


Fig.7 Anode current which can be turned off versus applied dV_D/dt^* : inductive load; $V_{GR} = 10$ V; $L_G \leq 0.5 \mu H$; $L_S \leq 0.25 \mu H$; $T_j = 120$ °C. * dV_D/dt is calculated from I_T/C_S .

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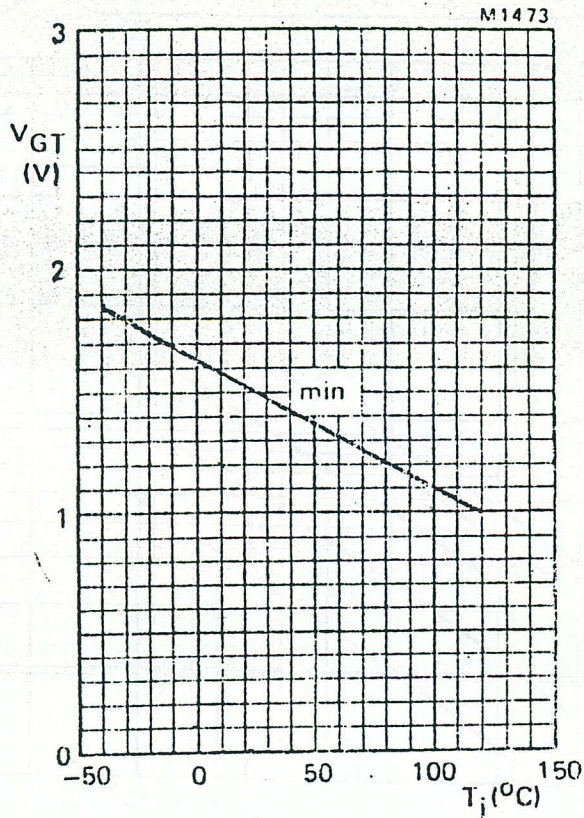


Fig. 8 Minimum gate voltage that will trigger all devices as a function of junction temperature; $V_D = 12$ V.

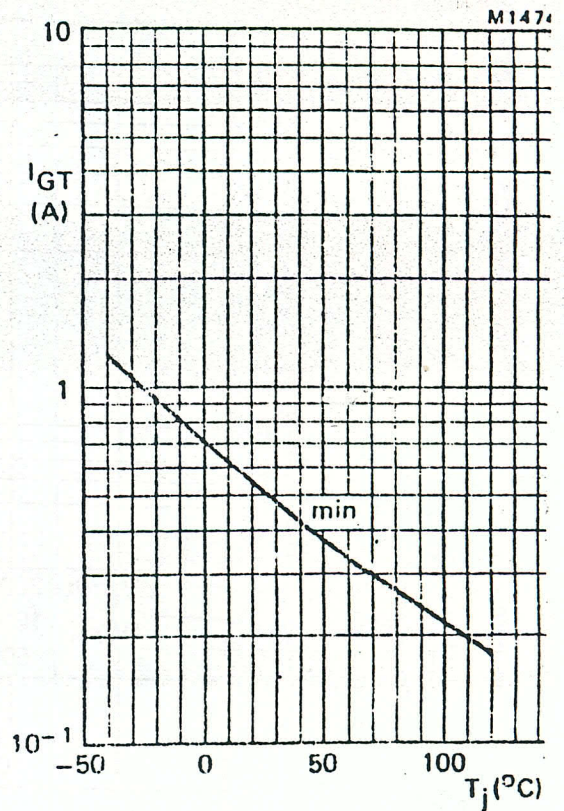


Fig. 9 Minimum gate current that will trigger all devices as a function of junction temperature; $V_D = 12$ V.

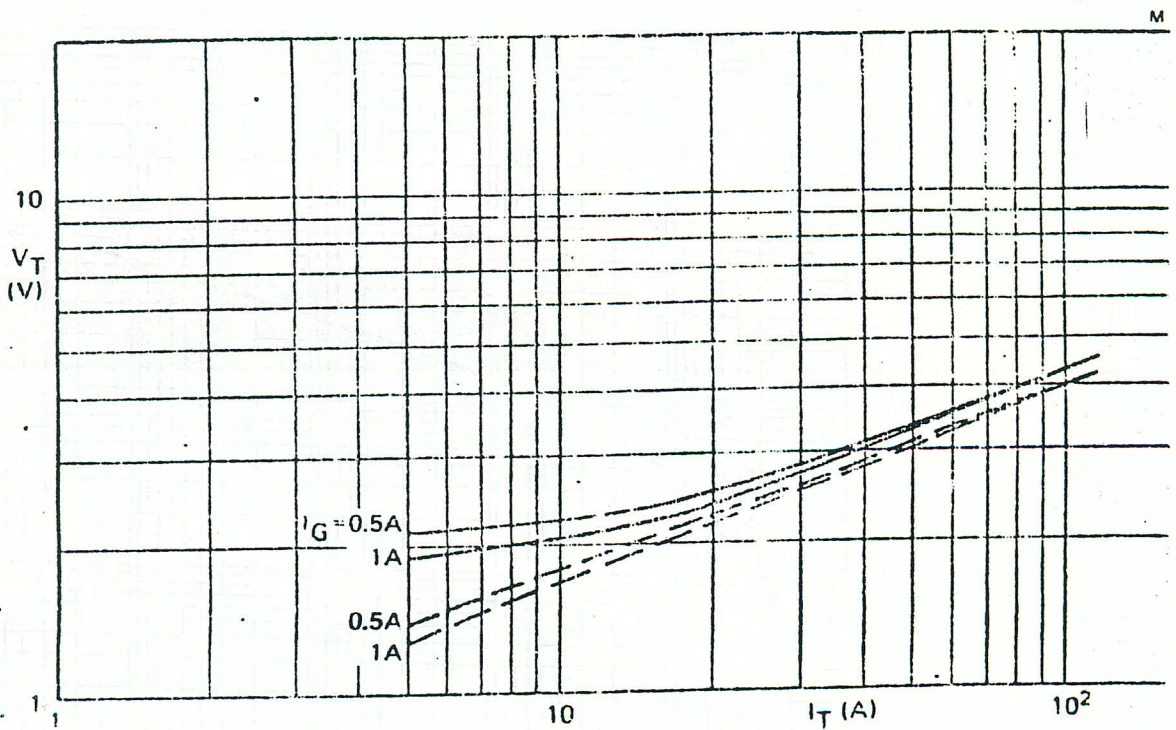


Fig. 10 Maximum V_T versus I_T : — $T_j = 25$ °C; - - - $T_j = 120$ °C.

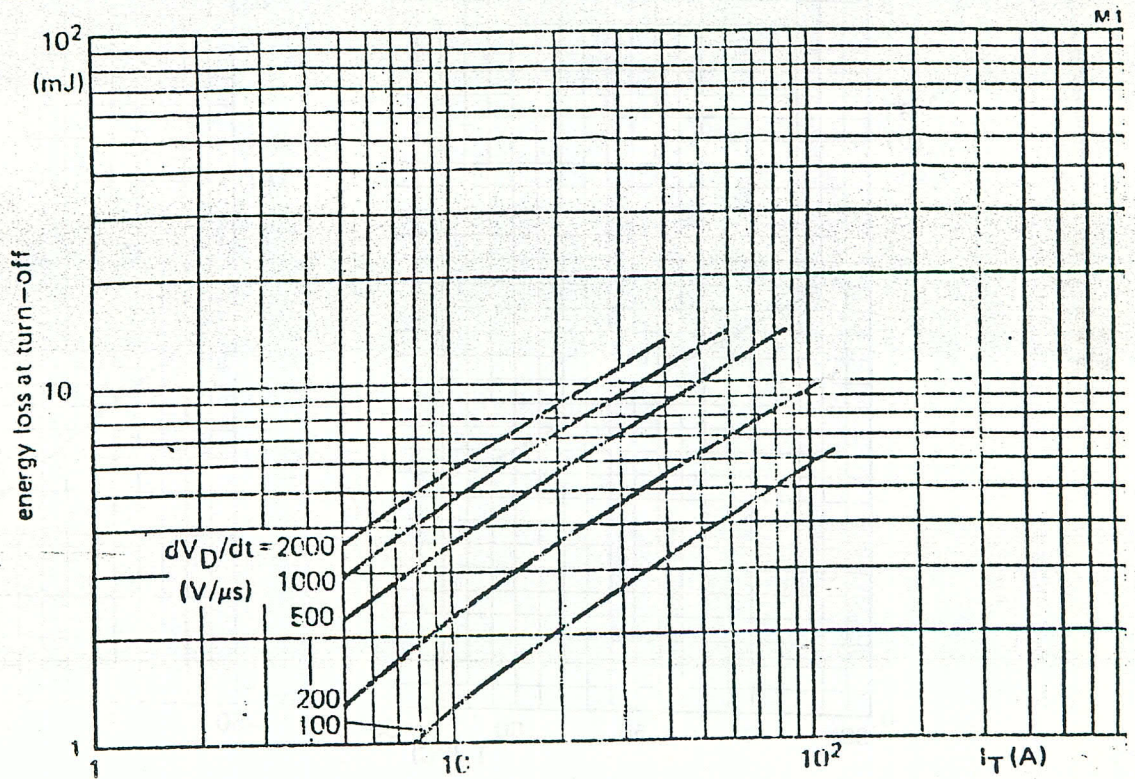


Fig.11 Maximum energy loss at turn-off (per cycle) as a function of anode current and app dV_D/dt (calculated from I_T/C_S); dV_D/dt linear up to $V_{Dmax} = 600$ V; $V_{GR} = 10$ V; $I_G = I_G \leq 0.5 \mu H$; $L_S \leq 0.25 \mu H$; $T_j = 120^\circ C$

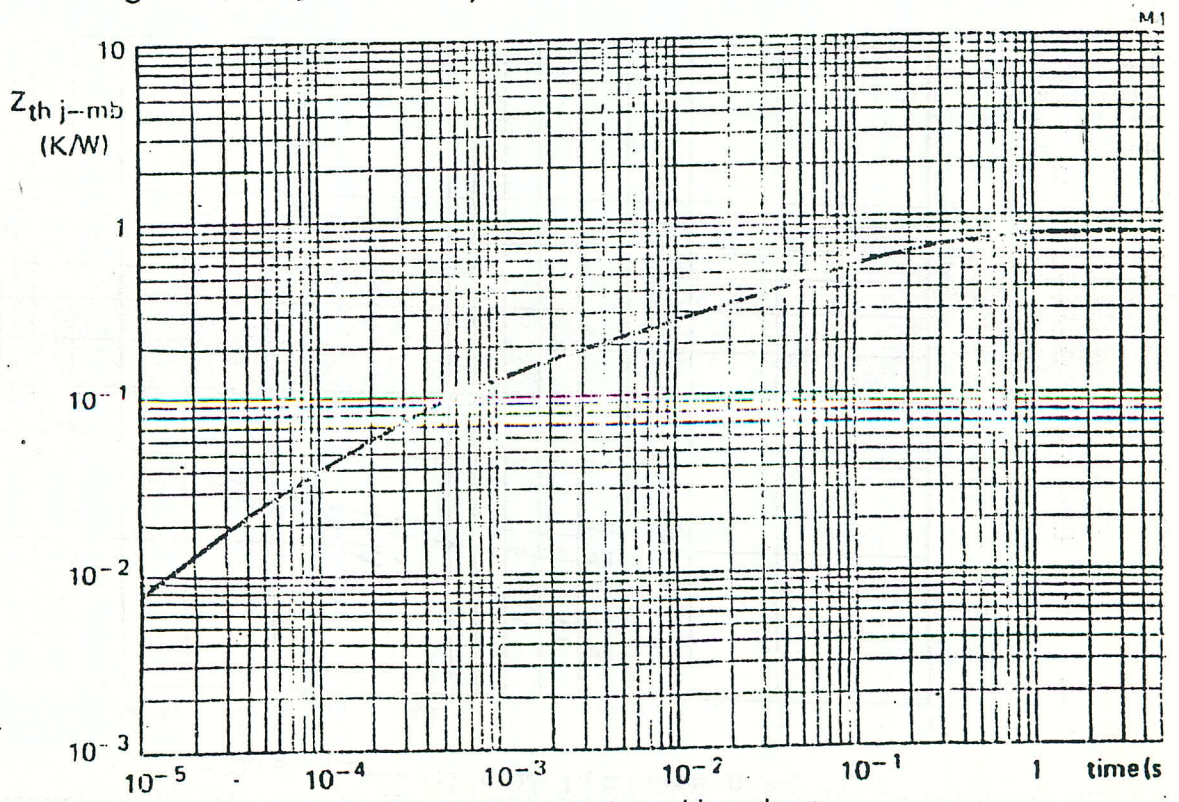


Fig.12 Transient thermal impedance.